Supplementary Document To: Optical crystallographic Study of Piezoelectric $K_x Na_{1-x} NbO_3$ (x = 0.4, 0.5 & 0.6) Single Crystals using Linear Birefringence

1. Crystal Growth, Compositional and Orientation Determination -

Figure 1(a) shows the optical image of as grown crystals (x = 0.5) embedded in the re-solidified flux. By successive boiling and treating by ultrasonic waves in water, crystals were separated from flux. Crystal with a cubic geometry were found to have maximum dimensions of about 6 mm X 6 mm X 2 mm. Figure 1(b) shows one of the crystal (x = 0.5) having planer dimensions of about 5 mm X 5 mm. After compositional homogenization by annealing at 1000°C, energy dispersive X-ray analysis (EDX) was performed to confirm the composition of crystals. Figure 2 shows the atomic mole % of Na and K ions in the crystals of three batches (x = 0.4, 0.5 and 0.6). For optical birefringence study, crystals with higher transparency were chosen from each batch of x = 0.4, 0.5 and 0.6 respectively.



Figure 1 Optical images showing (a) as grown crystals in KF – NaF matrix (b) One of the large size crystals.



Figure 2 Energy dispersive X-ray (EDX) analysis performed on crystals intended to have composition x = 0.4, 0.5 and 0.6.

Figure 3 shows x-ray diffraction pattern obtained for one of the major faces of a crystal (x = 0.5), confirming these crystals to be $\{100\}_{pc}$ oriented. This observation was further confirmed by electron backscattered diffraction analysis (EBSD) performed on two opposite major faces of these crystals.



Figure 3 x-ray diffraction pattern showing the presence of only {100} family peaks.

2. Birefringence Measurements –

Figure 4 shows the schematic diagram of the Metripol birefringence measurement system.¹



Figure 4 Schematic diagram of Metripol birefringence measurement system.

It consists of a monochromatic light source, a rotating polarizer followed by a sample stage. The transmitted light is allowed to go to the circular analyzer followed by a CCD detector. Intensity measured at each pixel of detector is given by Equation $1.^{1}$

$$I = I_o/2[1 + Sin(2\alpha - 2\varphi)Sin\delta]$$

Or

$$I = \frac{1}{2}I_o + \frac{1}{2}I_o \sin\delta \cos 2\varphi \sin 2\alpha - \frac{1}{2}I_o \sin\delta \sin 2\varphi \cos 2\alpha$$
(1)

Where I_o and φ are the transmittance of the sample and the angle between the minor axis of the indicatrix with an arbitrary coordination axis, respectively. δ is the phase difference introduced by the crystal to the transmitted light ray. To determine the values of all three components I_o , $|Sin\delta|$, and φ , the intensity of the transmitted light is measured for different values of the rotation angle α which the polarizer makes from a fixed reference.

Least square fitting method is used to determine the three parameters of interest, according to equation $(2)^{1}$

$$y(x) = a_0 + a_1 Sinx + a_2 Cosx$$
⁽²⁾

On comparing it with equation (1), "a" parameters are found to be

$$a_{o} = \frac{1}{2}I_{o}$$

$$a_{1} = \frac{1}{2}I_{o} \sin\delta \cos 2\varphi$$

$$a_{2} = \frac{1}{2}I_{o} \sin\delta \sin 2\varphi$$
(3)

If the polarizer is stepped through N steps in the process of collecting data, "a" parameters can be given as in equation (4).

$$a_{o} = \sum_{i=1}^{N} \frac{1}{N} y_{i}$$

$$a_{1} = \sum_{i=1}^{N} \frac{2}{N} y_{i} Sinx_{i}$$

$$a_{2} = \sum_{i=1}^{N} \frac{2}{N} y_{i} Cosx_{i}$$
(4)

Values for two parameters of interest $|Sin\delta|$ and ϕ can be determined from values of parameters "a" according to equation (5).¹

$$|Sin\delta| = \frac{\sqrt{(a_1^2 + a_2^2)}}{a_0}$$

$$\varphi = \frac{1}{2} \operatorname{arcSin}\left(-\frac{a_2}{\sqrt{(a_1^2 + a_2^2)}}\right) \tag{5}$$

3. Determination of Orientation Histogram -

To obtain the orientation histograms for three (x = 0.4, 0.5 and 0.6) compositions at different temperatures, φ false color images were obtained from an area of about 2.5 mm X 1.9 mm. Each of these images consisted of about 1.39 million (1360 X 1024) pixels, each representing a value of φ between 0° – 180°. Each histogram was created using these 1.39 millions φ values with the bin size of 1°.

4. Reference -

1. A. M. Glazer, J. G. Lewis and W. Kaminsky, *Proceedings: Mathematical, Physical and Engineering Sciences*, 1996, **452**, 2751-2765.